

Application No.	Applicant(s)	
10/086,036	BEAN, JAMES	
Examiner	Art Unit	
Jude J Jean-Gilles	2143	

SEAR Subclass 203-204 218-219 223-224	Date	Examiner
203-204 218-219		Examiner
218-219	044=4000=	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST tool: USPAT EPO JPO DERWENT	3/15/2005	JG		
PAM tool: Double patenting Effective Fing date	3/15/2005	JG		
Internet too NPLs IEEE onelook.com google.com	3/15/2005	JG		
Primary consulted: William Vaugh: Independent claims interpretation	3/15/2005	1G		
	3/15/2005	1G		

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